

SKM300GBD12T4



Fast IGBT4 Modules

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Features

- IGBT4 = 4. generation fast trench IGBT (Infineon)
- CAL4 = Soft switching 4. generation CAL-diode
- Isolated copper baseplate using DBC technology (Direct Bonded Copper)
- Increased power cycling capability
- With integrated gate resistor
- For higher switching frequencies up to 20kHz
- UL recognized, file no. E63532

Typical Applications*

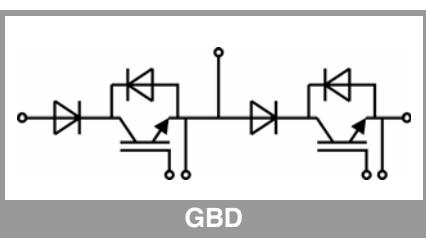
- Current source inverter

Remarks

- The Fig.1 to Fig.9 are based on measurements of the SKM300GBD12T4
- The series diodes (FWD) have the data of the inverse diodes of SKM400GB12T4
- Case temperature limited to $T_c = 125^\circ\text{C}$ max, recomm. Top = -40 ... +150°C, product rel. results valid for $T_j = 150^\circ\text{C}$

Absolute Maximum Ratings				Values	Unit		
Symbol	Conditions						
IGBT							
V_{CES}	$T_j = 25^\circ\text{C}$			1200	V		
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$		422	A		
		$T_c = 80^\circ\text{C}$		324	A		
I_{Cnom}				300	A		
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$			900	A		
V_{GES}				-20 ... 20	V		
t_{psc}	$V_{CC} = 800\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 1200\text{ V}$	$T_j = 150^\circ\text{C}$		10	μs		
T_j				-40 ... 175	$^\circ\text{C}$		
Inverse diode							
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$		56	A		
		$T_c = 80^\circ\text{C}$		43	A		
I_{Fnom}				50	A		
I_{FRM}	$I_{FRM} = 3 \times I_{Fnom}$			150	A		
I_{FSM}	$t_p = 10\text{ ms, sin }180^\circ, T_j = 25^\circ\text{C}$			180	A		
T_j				-40 ... 175	$^\circ\text{C}$		
Freewheeling diode							
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$		440	A		
		$T_c = 80^\circ\text{C}$		329	A		
I_{Fnom}				400	A		
I_{FRM}	$I_{FRM} = 3 \times I_{Fnom}$			1200	A		
I_{FSM}	$t_p = 10\text{ ms, sin }180^\circ, T_j = 25^\circ\text{C}$			1980	A		
T_j				-40 ... 175	$^\circ\text{C}$		
Module							
$I_{t(RMS)}$	$T_{\text{terminal}} = 80^\circ\text{C}$			500	A		
T_{stg}				-40 ... 125	$^\circ\text{C}$		
V_{isol}	AC sinus 50 Hz, $t = 1\text{ min}$			4000	V		

Characteristics					
Symbol	Conditions		min.	typ.	max.
IGBT					
$V_{CE(\text{sat})}$	$I_C = 300\text{ A}$ $V_{GE} = 15\text{ V}$ chiplevel	$T_j = 25^\circ\text{C}$		1.85	2.10
		$T_j = 150^\circ\text{C}$		2.25	2.45
V_{CE0}	chiplevel	$T_j = 25^\circ\text{C}$	0.8	0.9	V
		$T_j = 150^\circ\text{C}$	0.7	0.8	V
r_{CE}	$V_{GE} = 15\text{ V}$ chiplevel	$T_j = 25^\circ\text{C}$	3.50	4.00	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	5.17	5.50	$\text{m}\Omega$
$V_{GE(\text{th})}$	$V_{GE}=V_{CE}, I_C = 12\text{ mA}$		5	5.8	6.5
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25^\circ\text{C}$		4.0	mA
		$T_j = 150^\circ\text{C}$			mA
C_{ies}		$f = 1\text{ MHz}$		18.6	nF
C_{oes}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	1.16		nF
C_{res}		$f = 1\text{ MHz}$	1.02		nF
Q_G	$V_{GE} = -8\text{ V...+15 V}$			1700	nC
R_{Gint}	$T_j = 25^\circ\text{C}$			2.5	Ω



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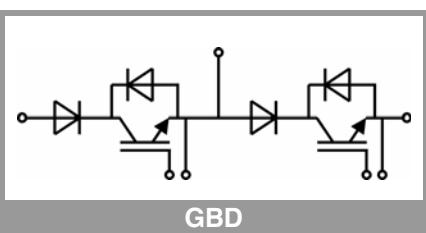
Typical Applications*

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Remarks

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Characteristics			min.	typ.	max.	Unit
Symbol	Conditions					
$t_{d(on)}$	$V_{CC} = 600 \text{ V}$ $I_C = 300 \text{ A}$ $V_{GE} = \pm 15 \text{ V}$ $R_{G\ on} = 1.5 \Omega$ $R_{G\ off} = 1.5 \Omega$ $di/dt_{on} = 7500 \text{ A}/\mu\text{s}$ $di/dt_{off} = 3350 \text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$ $T_j = 150^\circ\text{C}$ $T_j = 150^\circ\text{C}$ $T_j = 150^\circ\text{C}$ $T_j = 150^\circ\text{C}$ $T_j = 150^\circ\text{C}$		200 44 27 450 90 29		ns ns mJ ns ns mJ
E_{on}						
$t_{d(off)}$						
t_f						
E_{off}						
$R_{th(j-c)}$	per IGBT				0.11	K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 50 \text{ A}$ $V_{GE} = 0 \text{ V}$ chiplevel	$T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$		2.41 2.45	2.74 2.79	V
V_{F0}	chiplevel	$T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$		1.3 0.9	1.5 1.1	V
r_F	chiplevel	$T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$		22.2 31.0	24.8 33.8	mΩ
I_{RRM}	$I_F = 50 \text{ A}$	$T_j = 150^\circ\text{C}$				A
Q_{rr}	$di/dt_{off} = 7300 \text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$				μC
E_{rr}	$V_{GE} = \pm 15 \text{ V}$ $V_{CC} = 600 \text{ V}$	$T_j = 150^\circ\text{C}$				mJ
$R_{th(j-c)}$	per diode				0.94	K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 400 \text{ A}$ $V_{GE} = 0 \text{ V}$ chiplevel	$T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$		2.20 2.15	2.52 2.47	V
V_{F0}	chiplevel	$T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$		1.3 0.9	1.5 1.1	V
r_F	chiplevel	$T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$		2.3 3.1	2.5 3.4	mΩ
I_{RRM}	$I_F = 400 \text{ A}$	$T_j = 150^\circ\text{C}$		450		A
Q_{rr}	$di/dt_{off} = 8800 \text{ A}/\mu\text{s}$ $V_{GE} = \pm 15 \text{ V}$	$T_j = 150^\circ\text{C}$		68		μC
E_{rr}	$V_{CC} = 600 \text{ V}$	$T_j = 150^\circ\text{C}$		30.5		mJ
$R_{th(j-c)}$	per Diode				0.14	K/W
Module						
L_{CE}				15 20		nH
$R_{CC+EE'}$	terminal-chip	$T_C = 25^\circ\text{C}$ $T_C = 125^\circ\text{C}$		0.25 0.5		mΩ
$R_{th(c-s)}$	per module			0.02	0.038	K/W
M_s	to heat sink M6		3	5		Nm
M_t	to terminals M6		2.5	5		Nm
w				325		g



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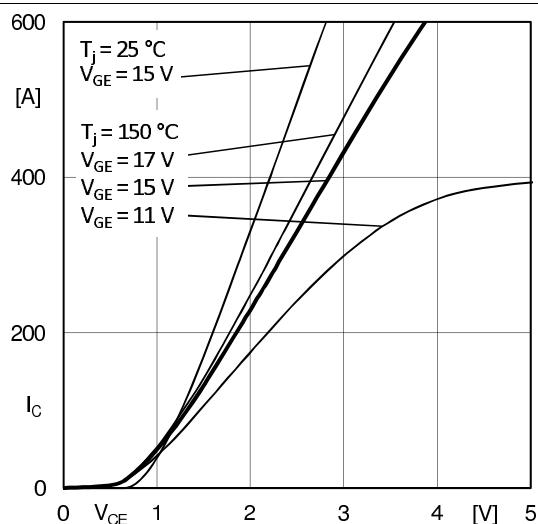


Fig. 1: Typ. output characteristic, inclusive $R_{CC} + EE'$

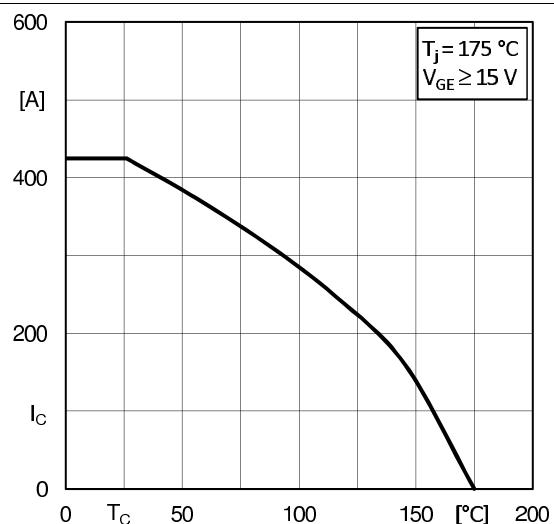


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

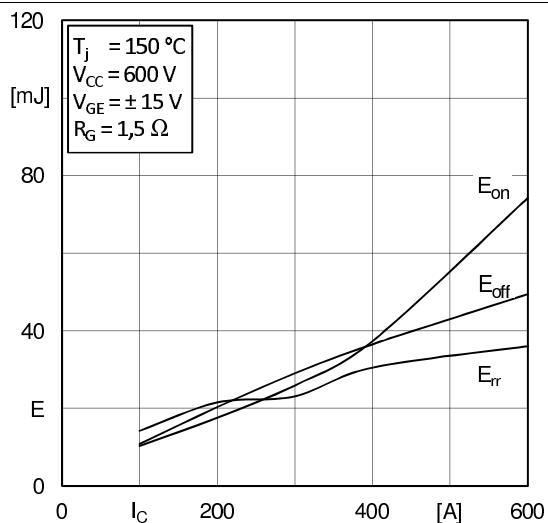


Fig. 3: Typ. turn-on /-off energy = f (I_C)

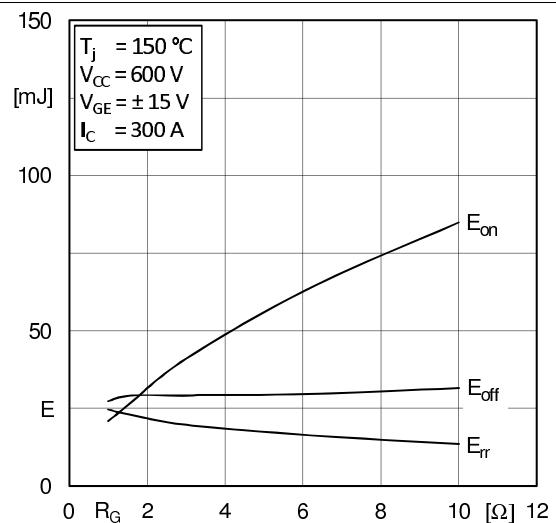


Fig. 4: Typ. turn-on /-off energy = f (R_G)

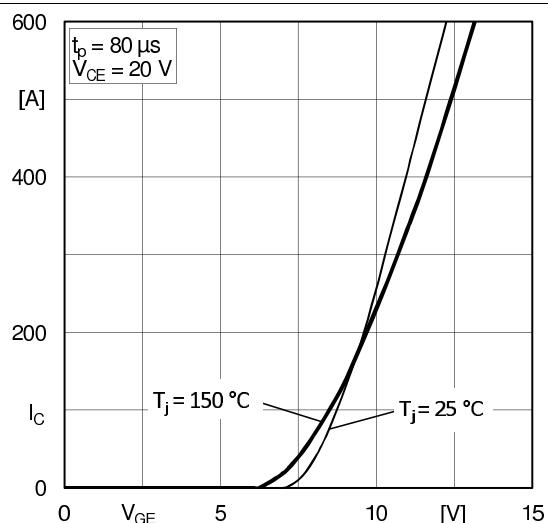


Fig. 5: Typ. transfer characteristic

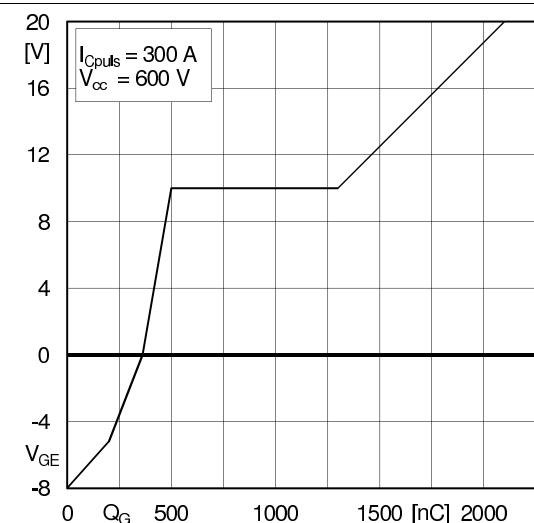


Fig. 6: Typ. gate charge characteristic

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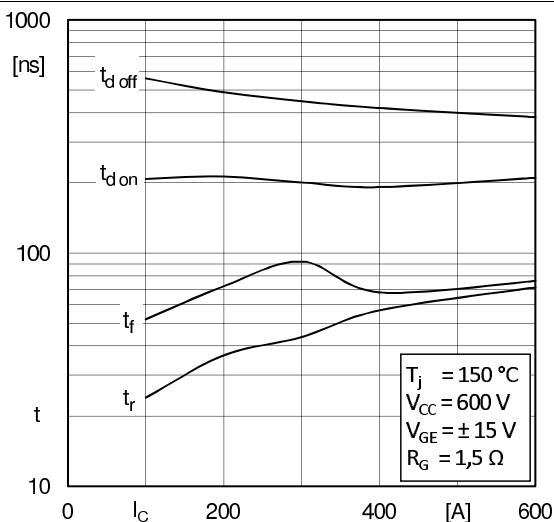


Fig. 7: Typ. switching times vs. I_C

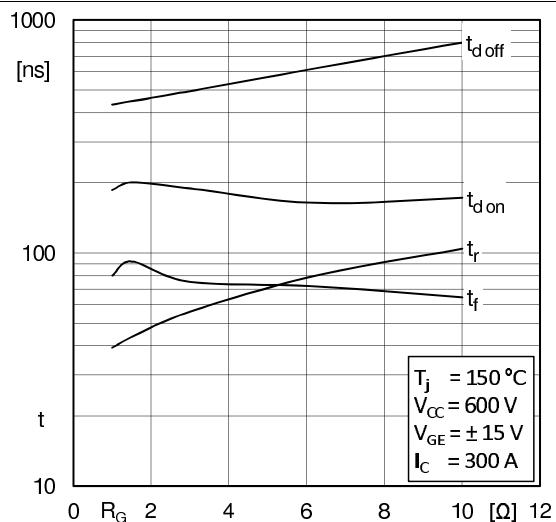


Fig. 8: Typ. switching times vs. gate resistor R_G

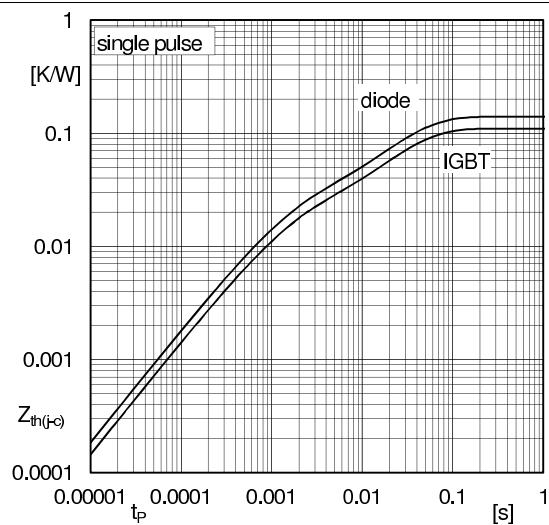


Fig. 9: Transient thermal impedance

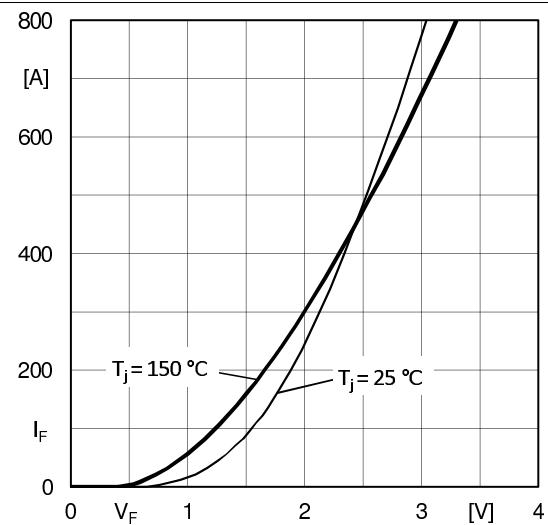


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC' + EE'}$

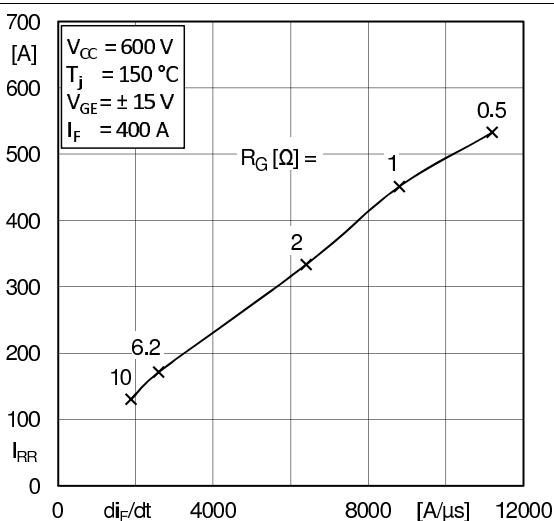


Fig. 11: CAL diode peak reverse recovery current

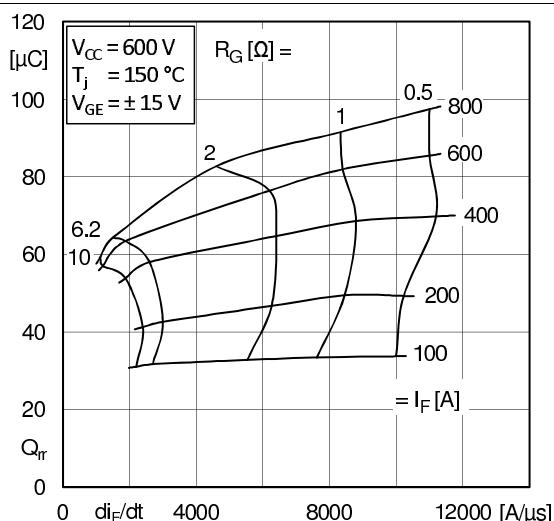
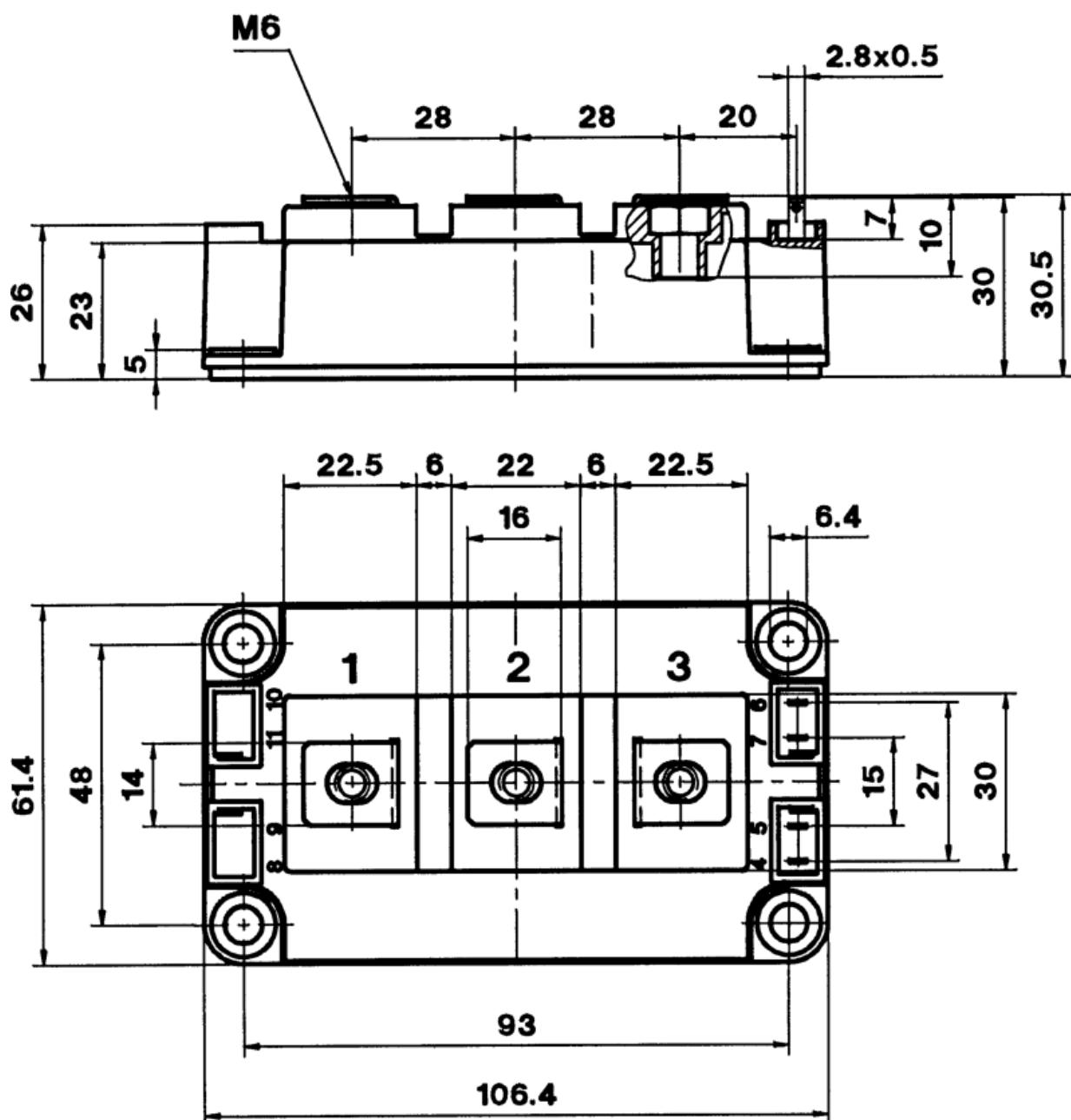


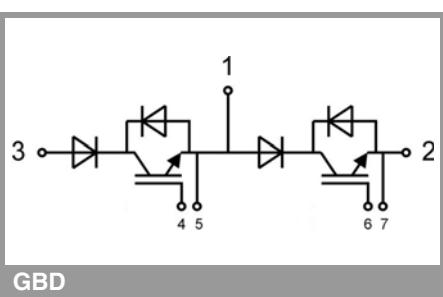
Fig. 12: Typ. CAL diode peak reverse recovery charge

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CASED56



SEMITRANS 3



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.